

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1211	(250/559.04,559.05,559.07,559.08,559.19,559.20,559.22,559.27,559.28).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/17 11:15
L2	752393	(insulat\$3 dielectric) near (film layer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:16
L3	6294	2 same (imag\$3 same thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:16
L4	0	1 and 3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:16
L5	1590	insulator same (imag\$3 same thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:17
L6	737	5 not 3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:17
L7	1	1 and 6	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:17

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L8	74	((insulat\$3 dielectric) near (film layer)) insulator) and 1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:18
L9	16	8 and (imag\$3 same thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:19
L10	41	8 and ((determin\$5 calculat\$3 measur\$5) near thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:20
L11	27	10 not 9	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:20
L12	2	11 not (((insulat\$3 dielectric) near (film layer)) and 1)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:28
L13	7	(thickness near map\$4) same library	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:29
L14	150	(thickness same imag\$3) same library	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:30

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L15	6294	2 same (imag\$3 same thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:32
L16	484	15 and ((determin\$5 calculat\$3 measur\$5) near thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:33
L17	1590	insulator same (imag\$3 same thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:39
L18	98	17 and ((determin\$5 calculat\$3 measur\$5) near thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:39
L19	37	18 not 16	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:40
L20	2	19 and (defect\$3 imperfect\$3 flaw)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:41
L21	7	19 and (database library)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:42

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L22	7	19 and ((database library) same imag\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:44
L23	231927	semiconduct\$3 near (film layer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:47
L24	30349	23 near insulat\$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:47
L25	1105	24 and ((determin\$5 calculat\$3 measur\$5) near thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:48
L26	6523	23 near dielectric	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:53
L27	295	26 and ((determin\$5 calculat\$3 measur\$5) near thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:54
L28	275	27 not 25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:54

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L29	3	28 and ((database library) same imag\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 11:54
L30	5156	(356/600,630,394,237.1,239.1,239.3,239.7,237.2,237.3,237.4,237.5).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/17 11:59
L31	3728	(438/7,14,16).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/17 11:59
L32	2657	(382/141,145,149,152).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/17 11:59
L33	898	(348/92,93,125,126,128).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2008/01/17 11:59
L34	29	(30 31 32 33) and 25	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:00
L35	15	(30 31 32 33) and 27	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:00
L36	15	35 not 34	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:00
L37	0	36 and ((database library) same imag\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 12:01
L38	1	36 and (database library)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 12:01
L39	2070	(30 31 32 33) and 2	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:10

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L40	495	39 and ((determin\$5 calculat\$3 measur\$5) near thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 12:10
L41	66	(30 31 32 33) and 15	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:14
L42	140	40 and (optic\$ same imag\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:16
L43	782	(30 31 32 33) and insulator	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:18
L44	149	43 and ((determin\$5 calculat\$3 measur\$5) near thickness)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 12:18
L45	35	44 not 40	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 12:19
L46	9	45 and (optic\$ same imag\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 12:29
L47	3	46 and (library database)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/17 12:32
L48	177636	((insulat\$3 dielectric) near (film layer)) insulator).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:35
L49	732	48 and ((determin\$5 calculat\$3 measur\$5) near thickness).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:45

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L50	0	49 and (imag\$3 same (database library)).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:46
L51	20	49 and (imag\$3 and (database library)).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:46
L52	0	51 and (imag\$3 same thickness).clm.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/17 12:50